## ESREF 2018 Conference

Provisional Programme Ver. 04 - 15-05-2018

Monday, October 1						Tuesday, October 2						Wednesday, October 3						Thursday, October 4						Friday, October 5		
Room A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area				
	TUTORIAL Reliability issues in power SiC and GaN				7 08:40 08:50 08:00 08:10 08:20 08:30 08:40 08:50 70:00		A-1 (5)	K-2 (5)	Industrial session	Exhibition	7 DR 40 DR 50 DR 50 DR 70 DR 70 DR 30 DR 40 DR 50 12 DD	E2-3 (4)	L-1 (4)	SS1-1 (4)	Industrial session	Exhibition	08:80 08:50 08:10 08:10 08:20 08:20 08:30 08:50 10:00				ECPE Workshop	Exhibition	7 0 ik 45 06 50 06 00 06 13 06 22 06 33 06 20 06 65 06 65 06 50			
	TUTORIAL	TUTORIAL	EFUG Workshop	Exhibition set up	10:10 10:20 10:30 10:40 10:60 11:00	Invited J. Stathis				Coffee break	10.10 10.20 10.30 10.40 10.50 11.00	Invited F. Altmann	Invited M.B. Tahoori		Workhop:	Coffee break	10:10 10:30 10:30 10:40 10:50 11:00				Workshop:	Coffee break	90:10 90:20 90:30 90:30 90:40 10:30 11:00			
	Reliability of packages for power devices	Dielectric reliability in microelectronics			11:10 11:20 11:20 11:20 11:20 11:20 12:10	E1-3 (3)	A-2 (3)	B1-1 (3)	Industrial session	Exhibition	11:10 11:20 11:30 11:40 11:50				Reliability in innovative Automotive ICs	Exhibition	11:10 11:20 11:30 11:40 11:60 12:00				Condition and health monitoring	Exhibition	11:18 11:20 11:30 11:40 11:50			
				Lunch	12:30 12:30 12:40 12:60 13:00					Lunch	12:10 12:20 12:30 12:40 12:50 13:00				ics	Lunch	12:10 12:20 12:30 12:40 12:60 13:00	Closing Session					12:00 12:10 12:20 12:20 12:30 12:40 13:00 13:10			
	TUTORIAL Moisture Modeling in Complex	TUTORIAL Introduction to the modern reliability			13:10 13:20 13:30 13:40 13:50 14:50 14:30	Invited J. Lutz	Invited N. Stojadinovic				13.10 13.20 13.30 13.40 13.60 14.00 14.10	Invited R. Ambat	Invited P. Pfäffli				13:30 13:30 13:30 13:40 13:60 14:00					Lunch	18:10 13:20 13:40 13:40 13:50 14:10 14:10			
Opening session  Keynote	Systems			Exhibition set up	16:20 16:30 16:40 16:50 16:00 16:10 16:20 16:20	E2-1 (5)	A-3 (5)	B1-2 (3) B2 (1)	Industrial session	Exhibition	14:20 14:30 14:40 14:50 15:00 15:10 15:20 15:30	F-3 (5)	L-3 (4)	SS1-3 (5)	Workshop: Applied robustness validation	Exhibition	14:30 14:30 14:40 14:50 15:00 15:10 15:20 15:30	APETT Symposium				Exhibition dismantling	16:20 16:30 16:40 16:50 16:00 16:10 16:20 16:30	Technical visit 1	Ter	
P. Gargini Keynote P.C. Kjaer				Coffee break	15:40 15:50 16:00 16:10 16:20 16:20 16:20 16:40			Best Paper IRPS  Best Paper IPFA	Industrial	Coffee break	15:40 15:50 16:00 16:10 16:20 16:30 16:40		Best paper ISTFA				15:80 15:50 16:00 16:10 16:30 16:30	APETT Symposium				Exhibition dismantling	15:40 15:50 16:00 16:13 16:20 16:30 16:30			
E1-1 (3)	F-1 (3)	C-1 (3)	K-1 (3)	Exhibition set up	96:50 17:00 17:10 17:20 17:30 17:40 17:60		H (4)	B3 (3)	session	Exhibition	16.50 17.00 17.10 17.20 17.30 17.40 17.50						16:50 17:00 17:10 17:30 17:30 17:40 17:50	-,				,	17:00 17:10 17:20 17:30 17:40			
				Aalborg City buffet	17:80 18:00 18:10 18:20 18:30 18:40 18:50 18:50 18:00 18:10		Poster	r session		Example:	17.50 18.00 18.10 18.20 18.20 18.40 18.50 18.50 18.10 18.10	Tour & Social dinner					17 AU 18400 18410						17:00 18:00 18:13 18:23 18:23 18:43 18:43 18:43 18:33 18:33			
				Oxy Dunet	19.30 19.40 19.40 19.30 20.00 20.10 20.30 20.30 20.40 20.90		Young P	rofessional Re	eception		19.30 19.40 19.60 20.00 20.10 20.30 20.30 20.40						19:30 19:30 19:40 19:50 20:00 20:10 20:30 20:30 20:40						19:30 19:30 19:40 19:50 20:00 20:10 20:20 20:30 20:30 20:40 20:40			

- Tracks
  A Quality and Reliability Assessment Techniques and Methods for Devices and Systems
  B1 Si-Technologies & Nanoelectronics: Hot Carriers, High-K, Gate Materials
  B2 Si Technologies & Nanoelectronics: Low-K. Cu Interconnects
  B3 Si-Technologies & Nanoelectronics: ESD, EM and Latch-up
  C Progress in Failure Analysis: Defect Detection and Analysis
  D Reliability of Microwave and Compound Semiconductors Devices
  E1 Power Devices Reliability Silicon and Passive
  E2 Power Devices Reliability Wide Bandgap Devices
  F Packaging and Assembly Reliability
  G MEMS. Sensors and Oroanic Electronics Reliability
  H Photonics Reliability
  I Extreme Environments and Radiation
  K Renewable Energies Reliability
  L Modeling for Reliability
  SS1- Reliability in Traction Applications